
**INFORMATION DISCLOSURE STATEMENT BY APPLICANT**

FEB 06 2003

Form PTO-1449 (Modified)  
(Use several sheets if necessary)**COMPLETE IF KNOWN**

Application Number	09/887,767
Confirmation Number	9072
Filing Date	June 21, 2001
First Named Inventor	Whonchee Lee
Group Art Unit	3723
Examiner Name	Alvin J. Grant
Attorney Docket No.	108298515US2

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of

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U.S. PATENT DOCUMENTS					
Examiner Initials*	Cite No.	U.S. Patent or Application		Name of Patentee or Inventor of Cited Document	Date of Publication or Filing Date of Cited Document
		NUMBER	Kind Code (if known)		
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AS	BM	6,068,787		Grumbine et al.	05/30/2000

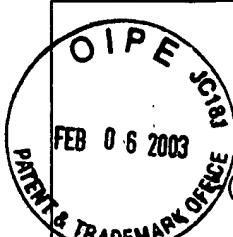
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Examiner Name	Alvin J. Grant

Sheet	1	of	4	Attorney Docket No.	108298515US2
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Examiner Initials*	Cite No.	U.S. Patent or Application		Name of Patentee or Inventor of Cited Document	Date of Publication or Filing Date of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		NUMBER	Kind Code (if known)			
AS	AA	U.S. Application No. 09/651,779 (Atty. Docket No. 10829.8515US)		Moore	Filed 08/30/2000	
AS	AB	U.S. Application No. 09/651,808 (Atty. Docket No. 4373US)		Chopra et al.	Filed 08/30/2000	
AS	AC	U.S. Application No. 09/653,392 (Atty. Docket No. MTI-31044)		Chopra et al.	Filed 08/31/2000	
AS	AD	U.S. Application No. 09/888,002 (Atty. Docket No. 10829.8515US3)		Lee et al.	Filed 06/21/2001	
AS	AE	U.S. Application No. 09/888,084 (Atty. Docket No. 10829.8515US3)		Lee et al.	Filed 06/21/2001	
AS	AF	U.S. Application No. 10/090,869 (Atty. Docket No. 10829.8544US)		Moore et al.	Filed 03/04/2002	
AS	AG	U.S. Application No. 10/230,463 (Atty. Docket No. 10829.8672US)		Lee et al.	Filed 08/29/2002	
AS	AH	U.S. Application No. 10/230,602 (Atty. Docket No. 10829.8674US)		Chopra	Filed 08/29/2002	
AS	AI	U.S. Application No. 10/230,628 (Atty. Docket No. 10829.8673US)		Lee et al.	Filed 08/29/2002	
AS	AJ	U.S. Application No. 10/230,970 (Atty. Docket No. 10829.8515US6)		Lee et al.	Filed 08/29/2002	
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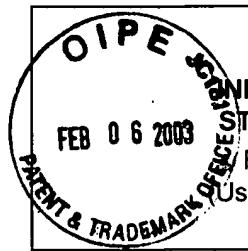
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AS	CB	WO	00/32356		Talieh	06/08/2000		
AS	CC	WO	00/59008		Talieh	10/05/2000		
AS	CD	WO	00/59682		Talieh	10/12/2000		

**OTHER PRIOR ART-NON PATENT LITERATURE DOCUMENTS**

Examiner Initials*	Cite No.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume issue number(s), publisher, city and/or country where published.	T
AS	CE	FRANKENTHAL, R.P. and EATON, D.H., "Electroetching of Platinum in the Titanium-Platinum-Gold Metallization on Silicon Integrated Circuits," <i>Journal of The Electrochemical Society</i> , Vol. 123, No. 5, pp. 703-706, May 1976.	

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<i>AG</i>	CF	BERNHARDT, A.F., CONTOLINI, R.J., MAYER, S.T., "Electrochemical Planarization for Multi-Level Metallization of Microcircuitry," <i>CircuiTree Journal</i> , Vol. 8, No. 10, pp. 38, 40, 42, 44, 46, and 48, Oct. 1995.	
<i>AG</i>	CG	HUANG, C.S. et al., "A Novel UV Baking Process to Improve DUV Photoresist Hardness," pp. 135-138.	
<i>AG</i>	CH	McGraw-Hill, <i>Concise Encyclopedia of Science &amp; Technology</i> , Sybil P. Parker, Editor in Chief, Fourth Edition, p. 367, McGraw-Hill, New York, New York, 1998.	
<i>AG</i>	CI	ATMI Table of Contents, presented at the Semicon West '99 Low Dielectric Materials Technology Conference, July 12, 1999, pp. 13-25.	
<i>AG</i>	CJ	Micro Photonics, Inc., CSM Application Bulletin, "Low-load Micro Scratch Tester (MST) for characterisation of thin polymer films," <a href="http://www.microphotonics.com/mstABpoly.html">http://www.microphotonics.com/mstABpoly.html</a> , 7/25/2002, 3 pages.	
<i>AG</i>	CK	Micro Photonics, Inc., "CSM Nano Hardness Tester," <a href="http://www.microphotonics.com/nht.html">http://www.microphotonics.com/nht.html</a> , 7/29/2002, 6 pages.	
<i>AG</i>	CL	PhysicsWorld – Table of Contents, PhysicsWeb, "Hard Materials," <a href="http://physicsweb.org/box/world/11/1/11/world-11-1-11-1">http://physicsweb.org/box/world/11/1/11/world-11-1-11-1</a> , 7/29/2002, 1 page.	

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